



<p style="text-align: center;"><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10506560</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>PETERSEN, LEIF</p>
	<p>Examiner</p> <p>Chen, Junpeng</p>	<p>Art Unit</p> <p>2618</p>

Class	SubClass	Date	Examiner
455	127.1; 127.2	11/14/2006	J.C.
330	149; 145; 137; 129; 52; 136; 9	11/14/2006	J.C.

U.S. Patent and Trademark Office	Part of Paper No.: 20061113
----------------------------------	-----------------------------

<b>Search Notes</b>  	Application/Control No.  10506560	Applicant(s)/Patent Under Reexamination  PETERSEN, LEIF
	Examiner Chen, Junpeng	Art Unit 2618

Notes	Date	Examiner
EAST Image and keyword search in USPAT, US-PG Pub, DERWENT, EPO, JPO and IBM, TDB	11/14/2006	J.C.
Consulted Fayyaz Alam, Alan Wong	11/14/2006	J.C.
U.S. Patent and Trademark Office		Part of Paper No.: 20061113